$0.15\substack{+0.10 \\ -0.05}$

Unit: mm

0.2±0.

MTM23110

Silicon P-channel MOSFET

For switching circuits

Features

- Low voltage drive (1.8 V, 2.5 V, 4 V)
- · Realization of low on-resistance, using extremely fine process

Absolute Maximum Ratings $T_a = 25^{\circ}C$

0 "						
Parameter	Symbol	Rating	Unit			
Drain-source surrender voltage	V _{DSS}	-12	V			
Gate-source surrender voltage	V _{GSS}	±8	V			
Drain current	ID	-4.0	А			
Peak drain current *1	I _{DP}	-16	А			
Power dissipation *2	P _D	500	mW			
Channel temperature	T _{ch}	150	°C			
Storage temperature	T _{stg}	-55 to +150	°C			

Note) *1: Pulse width $\leq 10 \ \mu$ s, Duty Cycle $\leq 1\%$

*2: Measuring on ceramic substrate at 40 mm \times 38 mm \times 0.1 mm Absolute maximum rating without heat sink for P_D is 150 mW



(0.425)

1.25±0.10 2.1±0.1

Marking Symbol: DM

0.3+0.1

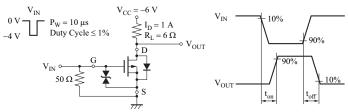
3

Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$								
Parameter	Symbol	Conditions	Min	Тур	Max	Unit		
Drain-source surrender voltage	V _{DSS}	$I_{\rm D} = -1 \text{ mA}, V_{\rm GS} = 0$	5 -12			V		
Drain-source cutoff current	I _{DSS}	$V_{\rm DS} = -12 \rm V, V_{\rm GS} = 0$	~		-1.0	μΑ		
Gate-source cutoff current	I _{GSS}	$V_{GS} = \pm 6.4 \text{ V}, V_{DS} = 0$			±10	μΑ		
Gate threshold voltage	V _{TH}	$I_D = -1.0 \text{ mA}, V_{DS} = -6.0 \text{ VO}$	- 0.3	- 0.65	-1.0	V		
Drain-source ON resistance ^{*1}		$I_{\rm D} = -1 {\rm A}, {\rm V}_{\rm GS} = -4.0 {\rm V}$		30	40	mΩ		
	R _{DS(on)}	$I_D = -0.5 \text{ A}, V_{GS} = -2.5 \text{ V}$		35	55			
		$I_D = +0.2 \text{ A}, V_{OS} = -1.8 \text{ V}$		50	75			
Forward transfer admittance *1	$ Y_{fs} $	$I_D = -1.0$ A, $V_{DS} = -10$ V, f = 1 kHz	3.5			S		
Short-circuit forward transfer capacitance (Common source)	CR	$V_{DS} = -10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$		1200		pF		
Short-circuit output capacitance (Common source)	C _{oss}			110		pF		
Reverse transfer capacitance (Common source)	C _{rss}			110		pF		
Turn-on time *2	t _{on}	$V_{DD} = -6 V, V_{GS} = 0 V \text{ to } -4 V, I_D = -1 A$		50		ns		
Turn-off time *2	t _{off}	$V_{DD} = -6 V, V_{GS} = -4 V \text{ to } 0 V, I_D = -1 A$		300		ns		

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

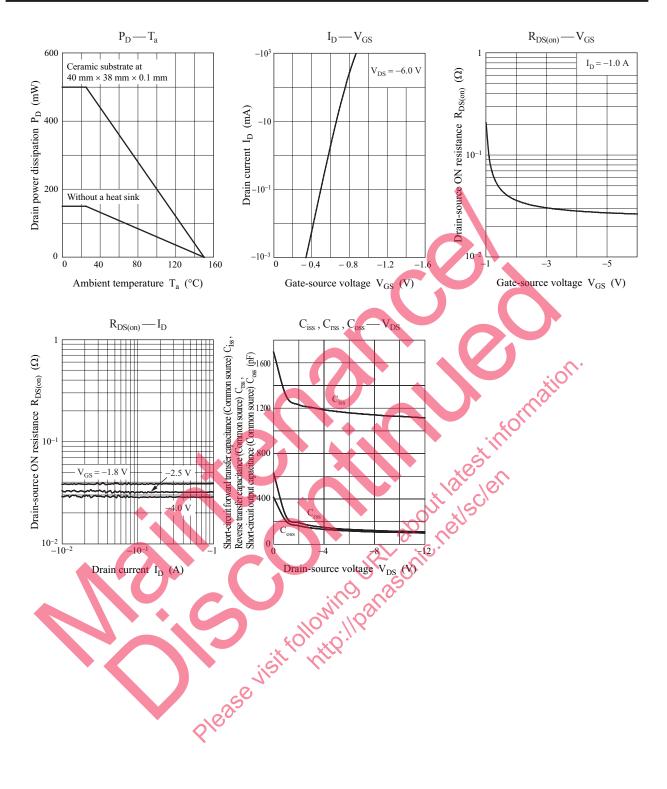
2. *1: Pulse measurement: Pulse width < 300 μ s, Duty Cycle < 2%

*2: ton , toff measurement circuit



MTM23110

Panasonic



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